

# 5977 EI Source Selection Guide

## Technical Overview

### Introduction

The Agilent GC/MSD system has long been a mainstay productivity tool in laboratories performing environmental, forensic toxicology, food, fine chemical, and other analyses. Each generation of the system has improved the data quality, ease of use and cost of operation, helping laboratory managers meet their performance goals during challenging economic times.

The ion source of an MSD instrument is critical to its performance. The efficiency of ionization and focusing of the ion beam into the quadrupole determine the sensitivity of the instrument. Many of today's MSD applications are run in electron ionization (EI) mode, requiring EI sources that optimize instrument performance. Agilent is the leader in development of ion source technology that can provide the high sensitivity and reliability needed for today's MSD applications.

The 5977 Series GC/MSD offers three EI source options. The traditional stainless steel source provides performance most similar to previous Agilent MSD instruments at a lower cost than the other ion sources. The inert source enables high sensitivity for active compounds that are most likely to bind to non-inert surfaces. The new Extractor EI Source delivers unparalleled sensitivity, while also being inert. This Technical Overview provides a guide for selection of the ion source most appropriate to the user's application.

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### Extractor EI Source

This innovative ion source has an extractor lens in place of the draw-out plate used in the other EI sources and it is made of an inert material. It is programmable up to 350 °C to deliver enhanced response for active compounds and late eluters. These unique features provide maximum, ultra-trace level sensitivity for a wide variety of compounds.

The extractor lens provides additional focus to the ion beam into the mass analyzer. A potential is applied to the extractor lens which “pulls” the ions out of the ionization chamber, adding to the push provided by the repeller voltage (Figure 1). The result is a significant increase in the number of ions analyzed, improving the true sensitivity of the instrument.

There are three available aperture sizes for the Extractor EI Source, as well as the two other sources: 3, 6, and 9mm (Table 1). Generally, the 3mm aperture provides the best sensitivity. Selecting one of the larger aperture sizes enables analysis of higher concentrations of target compounds. Increasing aperture diameters also reduces the residence or interaction time and provides higher effective inertness for fragile compounds.

The Extractor EI Source can be operated in the higher sensitivity mode of extraction tuning or in standard mode in which it will behave in the same way as the standard stainless and inert sources. The ability to change between extractor and repeller-only mode is controlled by the software and does not require any physical changes.

A video description of the Extractor EI Source is available at [http://www.chem.agilent.com/en-US/promotions/Pages/GC-GCMS\\_resolve.aspx](http://www.chem.agilent.com/en-US/promotions/Pages/GC-GCMS_resolve.aspx).

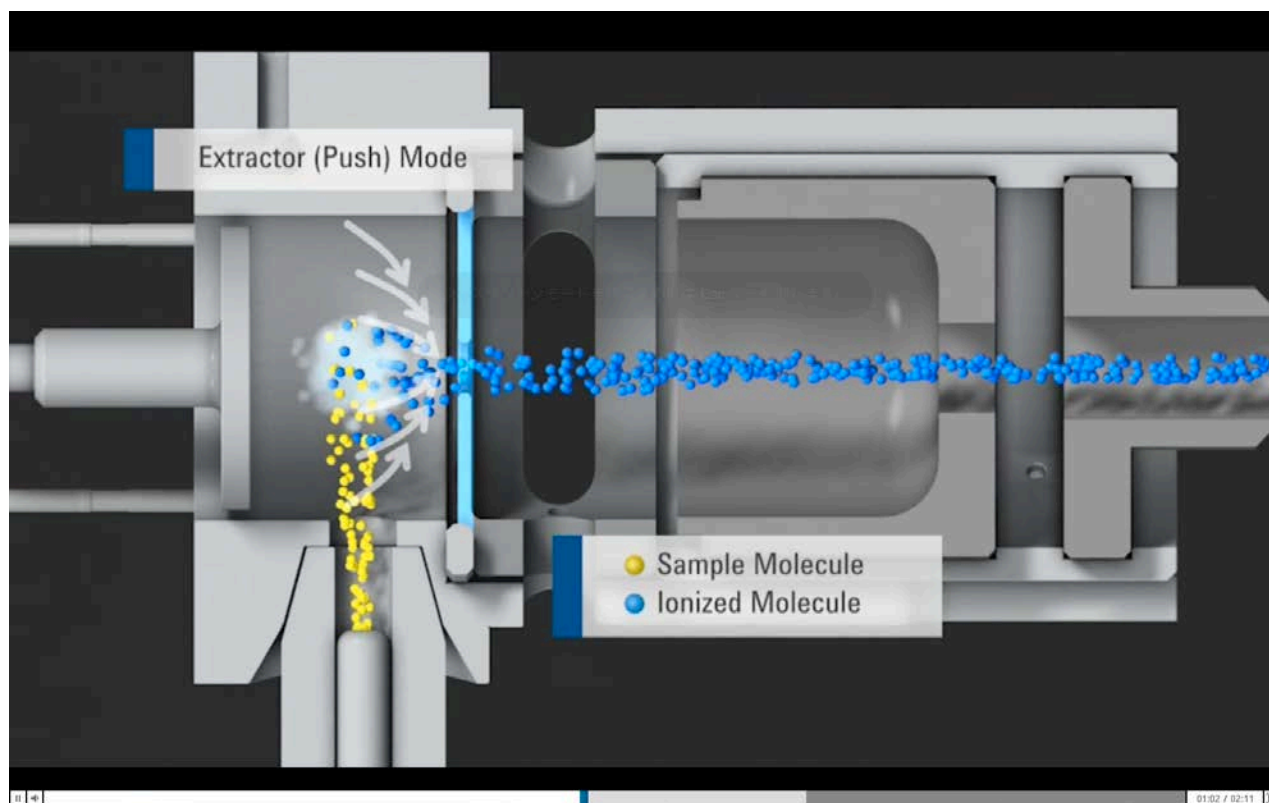


Figure 1. The new Extractor EI source for the 5977 GC/MSD, illustrating the “pull” mode which increases the number of ions introduced into the chamber.

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### Inert Ion Source

To ensure accurate quantification and high sensitivity, the entire GC/MSD flow path must be highly inert, including the detector surfaces. The inert ion source is made of the same inert material used in the Extractor EI Source and is programmable to 350 °C, enabling trace level detection and SVOC and VOC analyses (Table 2).

Table 1. Aperture Diameters Available for the 5977A Ion Sources

Aperture diameter	3mm	6mm	9mm
Stainless Steel Source	05971-20134*	--**	--
Inert Source	G2589-20100	G2589-20045	--
Extractor EI Source	G3870-20444	G3870-20448	G3870-20449

\*Part number

\*\* It is mechanically possible to install the 6mm drawout lens of the Inert Source into the Stainless Steel Source.

### Source and Tune Selection Guidance

Choosing the most appropriate source configuration and tune can have a significant effect on the success of an application (Table 3). The guidelines outlined here are meant to be general suggestions as starting points, and application-specific method development should be performed to ensure the best operating conditions. A description of the various tune modes and their use is provided in Table 4.

The user should also read and understand the Gain QuickStart Note before attempting to optimize any method or configuration.

### Stainless Steel Ion Source

The most cost-effective source for picogram to high nanogram sensitivity and for obtaining spectra most similar to legacy instruments is the stainless steel ion source, which is programmable up to 350 °C (Table 2).

Table 2. Source Selection for Various Applications

Application	Source(s)	Draw-out/Extractor Lens (mm)	Tune
Ultra-trace level (low fg – low ng)	Extractor EI	3	Etune
Trace level (fg – ng)	Extractor EI, Inert	3	Etune, Atune
Mid to high-level (pg – high ng)	Extractor, Inert, Stainless Steel	6,9	Atune
Obtain spectra closest to older instruments	Stainless Steel	3	Stune
VOC P&T – (BFB)	Extractor EI, Inert	6	BFB Autotune
SVOC (DFTPP)	Extractor EI, Inert	6	DFTPP

Table 3. Source Configurations and Supported Tunes

Source	Etune	Atune	BFB_atune	Iomass	stune	DFTPP	BFB
Stainless Steel	--*	✓	--	✓	✓	✓	✓ <sup>‡</sup>
Inert	--*	✓	✓ <sup>†</sup>	✓	✓	✓	✓ <sup>‡</sup>
Extractor EI	✓	✓	✓ <sup>†</sup>	✓	✓	✓	✓ <sup>‡</sup>

\* Etune can be executed from the tune menu with a non-extractor source but will produce only an atune

† BFB\_Atune requires the use of the 6mm draw-out plate/extraction lens

‡ BFB\_Atune is the preferred tune. See Application Note 5991-0029EN.

## EI Tune Options

In the Tune menu in the **Tune and Vacuum Control** view there are several options for tune selection. The top two options are mechanisms to run part or the entire active tune. The remaining menu options are tunes for specific purposes and are described below.

Table 4. Description of the Tune Options for the 5977A Ion Sources

Tune menu items (default tune filenames as *.U )	Description
Tune MSD	Performs the type of tune that is embedded in the active tune.
QuickTune	Provides a fine tuning to ensure acceptable response, resolution and accurate mass assignment.
Autotune (Atune.U)	The standard repeller-based tune of the 5973 and 5975.
Extraction source tune (Etune.U)	Used with the Extractor EI Source to provide the highest sensitivity. Equivalent to Atune when used with inert or stainless sources.
BFB Autotune (BFB_Atune.U)	Used in conjunction with Atune to meet USEPA BFB tuning criteria. Requires the use of 6 mm draw-out/extraction lens and operates in standard repeller-based tuning mode.
Low Mass Autotune (Lomass.U)	Identical to Autotune, except it tunes on masses 69, 131, and 219 instead of 69, 219, and 502. Intended for low molecular weight applications and natural gases under 250 daltons.
Standard Spectra Tune (Stune.U)	Ensures standard response over the full mass range. Specifically, PFTBA mass 69 is the base peak, mass 219 is between 35 and 99%, and mass 502 is >1%. This is a lower sensitivity tune used to better match legacy libraries created using the 5971 or 5972 MSDs.
DFTPP	A specific target tune used for USEPA semi-volatile analysis (8270 methods).
BFB	A specific legacy target tune used for VOC analysis. It does not provide the same sensitivity and stability as BFB Autotune. Provides continuity for established SOPs and for users with a preference for target tuning. See Application Note 5991-0029EN for a description of the recommended procedure for VOC analysis.

## Available EI Sources for the 5977A GC/MS

Source	Benefit	Product number (Spare parts)
Stainless	Inexpensive	G2591D
Inert	Reduced activity	G2591B
Extractor EI Source	Reduced activity Highest sensitivity	G2591C

5991-2106EN

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